

Notice of References Cited	Application/Control No. 10/075,750	Applicant(s)/Patent Under Reexamination GAUTHIER ET AL.	
	Examiner Cassandra Cox	Art Unit 2816	Page 1 of 1

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	B	US-6,441,602	08-2002	Eckhardt et al.	324/76.53
	C	US-6,333,905	12-2001	Kobayashi et al.	369/59.11
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.